





ISO 4287 - Roughness (S-L)			
F: None			
S-filter ( $\lambda_s$ ): None			
L-filter ( $\lambda_c$ ): Gaussian, 0.25 mm, Ends not cut			
Evaluation length: All $\lambda_c$ (1)			
Amplitude parameters			
Rp	0.6875	µm	
Rv	0.4751	µm	
Rz	1.163	µm	
Rc	0.4644	µm	No averaging (single value)
Rt	1.163	µm	
Ra	0.1399	µm	
Rq	0.1784	µm	
Rsk	0.3977		
Rku	3.817		
Material ratio parameters			
Rmr	96.55	%	$c = 1 \mu\text{m}$ below highest peak
Rdc	0.2954	µm	$p = 20\%$ , $q = 80\%$
<b>Warnings</b>			
The workflow already contains a 'Metrological filter' operator.			

ISO 4287 - Roughness (S-L)			
F: None			
S-filter ( $\lambda_s$ ): None			
L-filter ( $\lambda_c$ ): Gaussian, 0.25 mm			
Evaluation length: All $\lambda_c$ (1)			
Amplitude parameters			
Rp	0.6837	µm	
Rv	0.9242	µm	
Rz	1.608	µm	
Rc	0.6194	µm	No averaging (single value)
Rt	1.608	µm	
Ra	0.2485	µm	
Rq	0.3031	µm	
Rsk	-0.04356		
Rku	2.503		
Material ratio parameters			
Rmr	83.31	%	$c = 1 \mu\text{m}$ below highest peak
Rdc	0.5597	µm	$p = 20\%$ , $q = 80\%$
<b>Warnings</b>			
The workflow already contains a 'Metrological filter' operator.			

## ISO 25178 - Primary surface

F: [Workflow] Leveled (LS-plane)

F: Leveled (LS), Angle  $-1.032e-05^\circ$ ,  $-3.114e-07^\circ$

S-filter ( $\lambda_s$ ): Gaussian,  $0.8 \mu\text{m}$

### Height parameters

Sq	1.082	$\mu\text{m}$	
Ssk	-0.4458		
Sku	2.418		
Sp	2.522	$\mu\text{m}$	
Sv	3.520	$\mu\text{m}$	
Sz	6.042	$\mu\text{m}$	
Sa	0.8994	$\mu\text{m}$	



